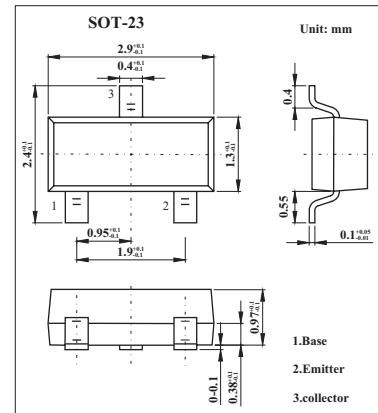


PNP Epitaxial Planar Silicon Transistor

2SA1434

■ Features

- Adoption of FBET process.
- High DC current gain ($hFE=500$ to 1200).
- Low collector-to-emitter saturation voltage ($V_{CE(sat)} \leq 0.5V$).
- High V_{EB0} ($V_{EB0} \geq 15V$).



■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Collector-base voltage	V _{CBO}	-60	V
Collector-emitter voltage	V _{CEO}	-50	V
Emitter-base voltage	V _{EB0}	-15	V
Collector current	I _C	-100	mA
Collector current (pulse)	I _{cp}	-200	mA
Collector dissipation	P _C	200	mW
Junction temperature	T _j	125	°C
Storage temperature	T _{stg}	-55 to +125	°C

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Collector cutoff current	I _{CBO}	V _{CB} = -40V, I _E =0			-0.1	µA
Emitter cutoff current	I _{EB0}	V _{EB} = -10V, I _C =0			-0.1	µA
DC current gain	h _{FE}	V _{CE} = -5V , I _C = -10mA	500	800	1200	
Gain bandwidth product	f _T	V _{CE} = -10V , I _C = -10mA		100		MHz
Output capacitance	C _{ob}	V _{CB} = -10V , f = 1.0MHz		4.8		pF
Collector-emitter saturation voltage	V _{CE(sat)}	I _C = -50mA , I _B = -1mA		-0.2	-0.5	V
Base-emitter saturation voltage	V _{BE(sat)}	I _C = -10µA , I _B = -1mA		-0.8	-1.1	V
Collector-base breakdown voltage	V _{(BR)CBO}	I _C = -10µA , I _E = 0	-60			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C = -1mA , R _{BE} = ∞	-50			V
Emitter-base breakdown voltage	V _{(BR)EBO}	I _E = -10µA , I _C = 0	-15			V

■ Marking

Marking	FL
---------	----